

PATENT ABSTRACTS OF JAPAN

(11)Publication number : 07-146340

(43)Date of publication of application : 06.06.1995

(51)Int.Cl. G01R 31/28
G11C 29/00
H01L 21/66

(21)Application number : 05-315988 (71)Applicant : NEC CORP
(22)Date of filing : 22.11.1993 (72)Inventor : MAEDA TETSUNORI

(54) DEVICE AND METHOD FOR EDITING REPAIR DATA

(57)Abstract:

PURPOSE: To improve the yield of a repair data editing device and reduce man- hours of the device by deleting overlapping data from a repair data file.

CONSTITUTION: At the time of restarting inspections after abnormality eliminating process is completed when abnormality is detected during the course of wafer inspections, the inspections are restarted from, for example, a third wafer when the abnormality eliminating process is completed after a fifth wafer is inspected. In this case, repair data are automatically edited after a seventh wafer is inspected. In other words, overlapping parts exists in an inspection history data file and repair data file. The overlapping parts mean the parts from the wafer number of the third wafer to the end of the data of the fifth wafer and the title of the data. Such overlapping parts are deleted by the automatic edition. Namely, whether or not the repair data are normal is confirmed by comparing the storing order of waver numbers between the two files and one of the overlapping repair data is deleted by obtaining the repair data. Therefore, normal data files which do not contain any overlapping data are obtained.

データタイトル	データタイトル
ウェハ番号1	1番目のウェハ番号
ウェハ番号2	2番目のウェハ番号
ウェハ番号3	3番目のウェハ番号
ウェハ番号4	4番目のウェハ番号
ウェハ番号5	5番目のウェハ番号
データタイトル	データタイトル
ウェハ番号3	3番目のウェハ番号
ウェハ番号4	4番目のウェハ番号
ウェハ番号5	5番目のウェハ番号
ウェハ番号6	6番目のウェハ番号
ウェハ番号7	7番目のウェハ番号

LEGAL STATUS

[Date of request for examination] 29.03.1994

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number] 2616413

[Date of registration] 11.03.1997

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's
decision of rejection]

[Date of extinction of right]

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